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in situ micro-X-ray diffraction (Kossel-technique)

Any technique which utilizes the diffraction of X-rays generated in a microstructural domain of a solid under bombardment with a finely focused electron beam, thus providing an X-ray diffraction pattern of this microstructural domain. The pattern can be recorded with a film either on the reflection or transmission side of the specimen (in the latter case the crystalline sample has to be a thin film or a small particle).

Source:
PAC, 1983, *55*, 2023 *(Nomenclature, symbols and units recommended for in situ microanalysis (Provisional))* on page 2025

